

**Search Notes**

Application/Control No.

09/766,270

Examiner

Chau Nguyen

Applicant(s)/Patent under  
Reexamination

SEKIDO ET AL.

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	522-523	9/28/2004	CN
715	530	9/28/2004	CN
715	531	9/29/2004	CN
715	539	9/29/2004	CN
715	540	9/29/2004	CN
707	102	9/29/2004	CN
715	522-523	11/22/2005	CN
715	530-531	11/22/2005	CN
715	539-540	11/22/2005	CN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	09/28/2004	CN
	9/29/2004	CN
	10/4/2004	CN
	10/12/2004	CN
	10/20/2004	CN
Updated Search on East Reports	11/22/2005	CN
NPL Search on IEEE Database	11/23/2005	CN
Updated Search on East Reports	6/8/2006	CN